

Fig. 1A

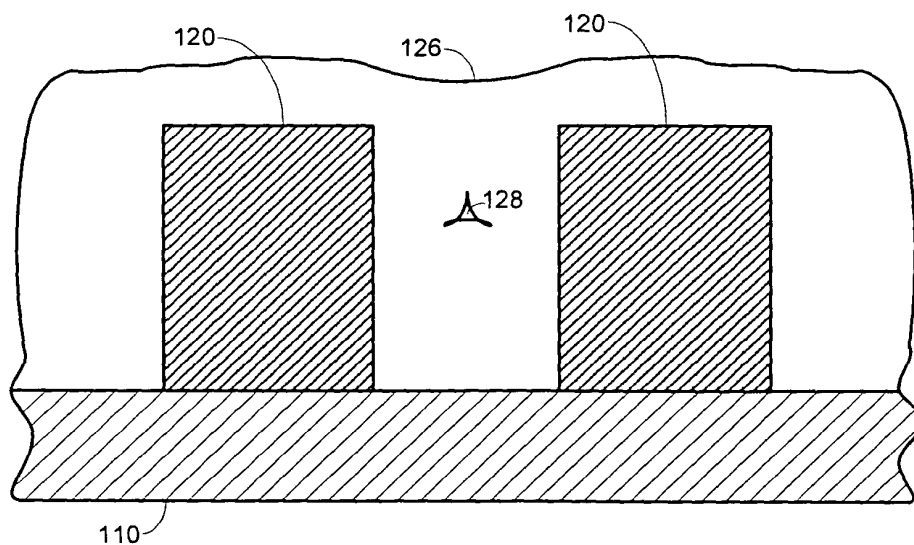


Fig. 1B

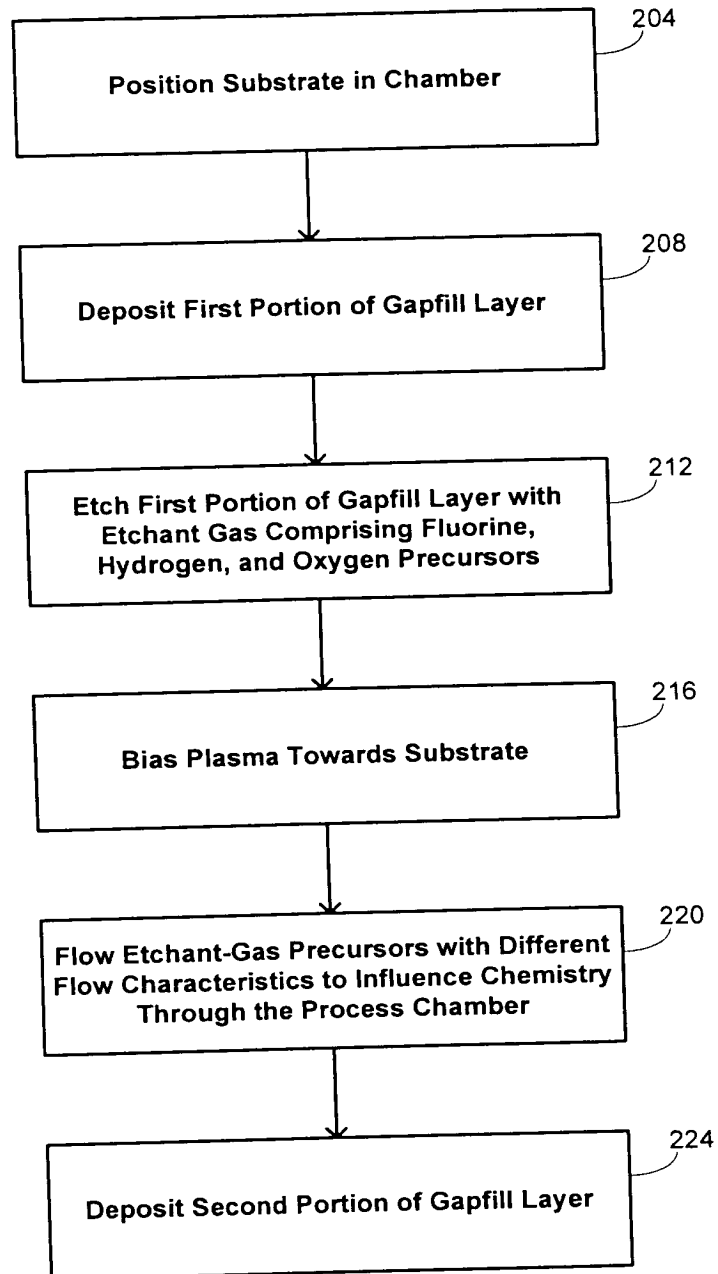


Fig. 2A

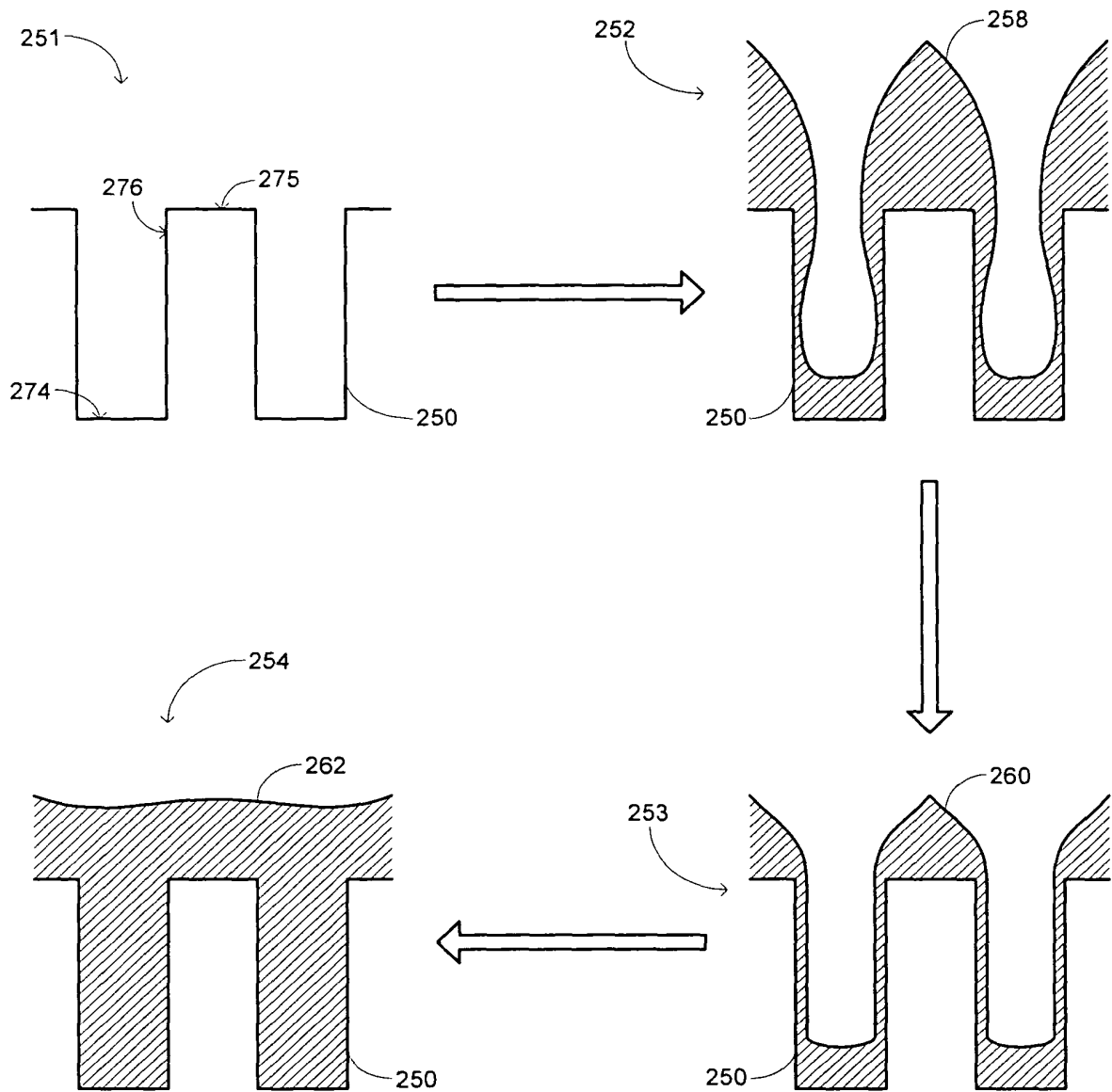


Fig. 2B

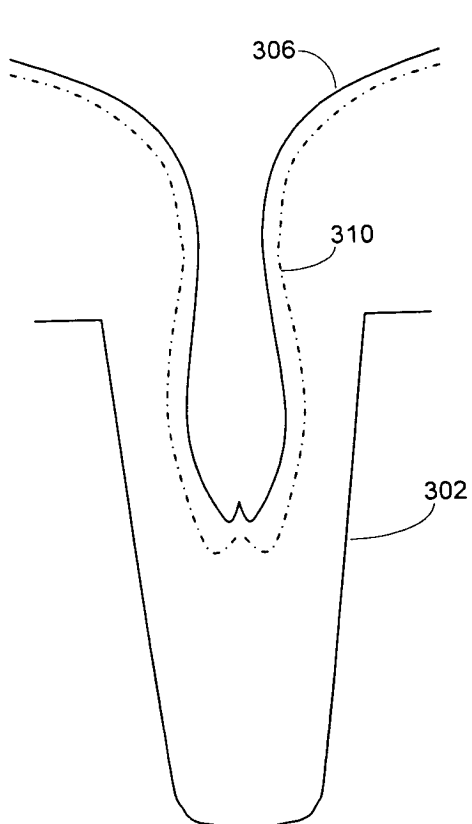


Fig. 3A

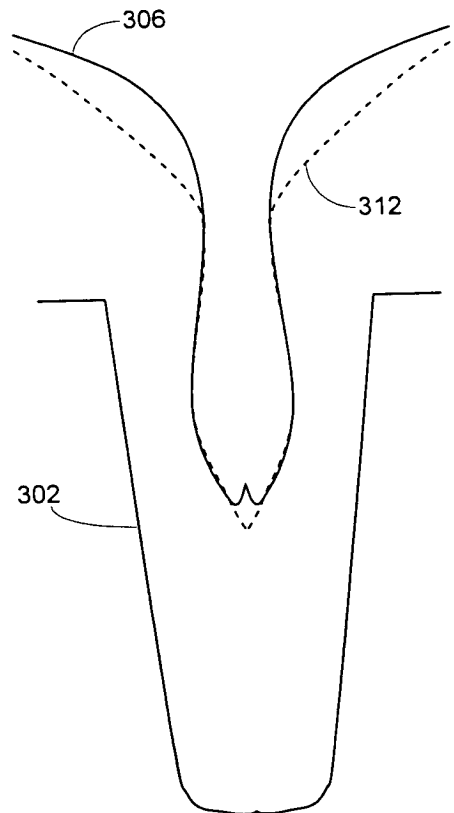


Fig. 3B

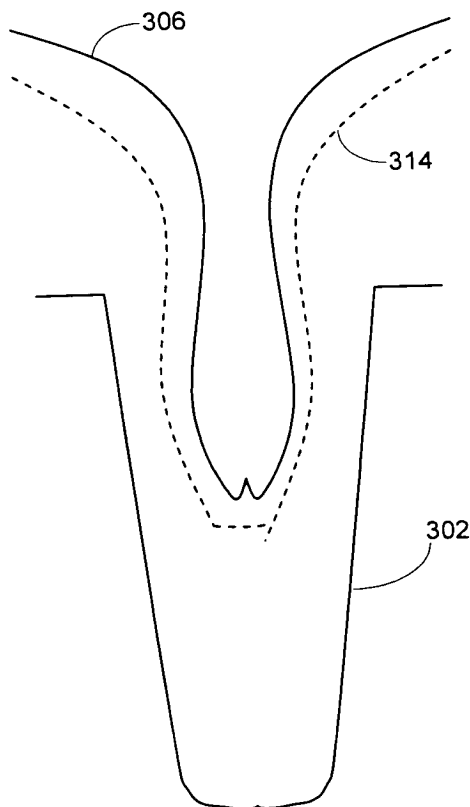


Fig. 3C

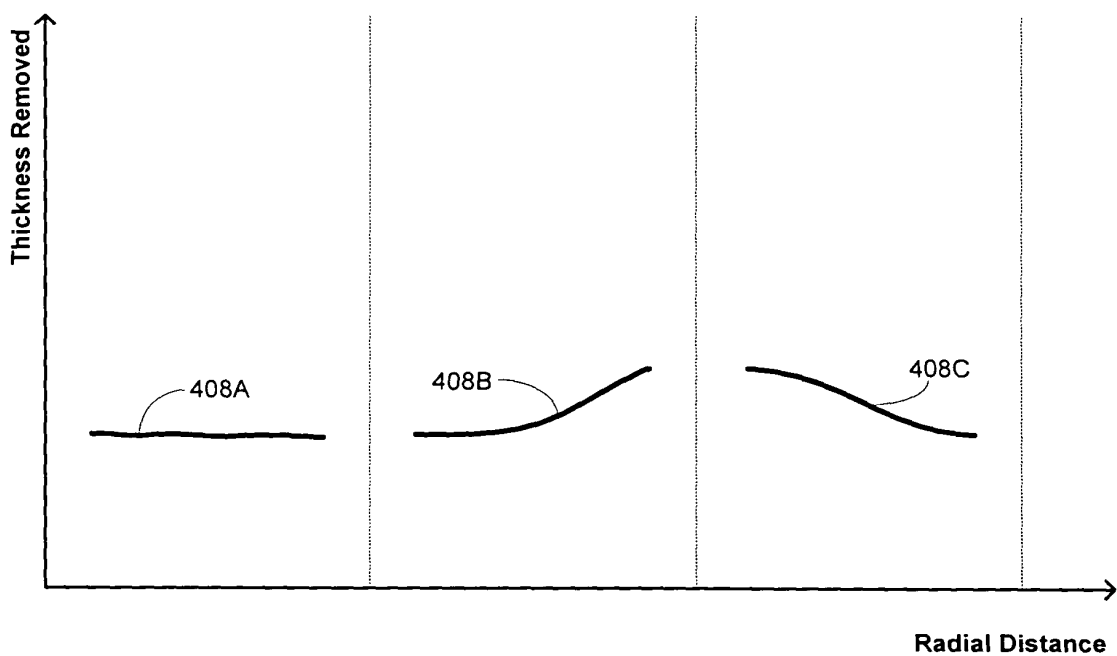
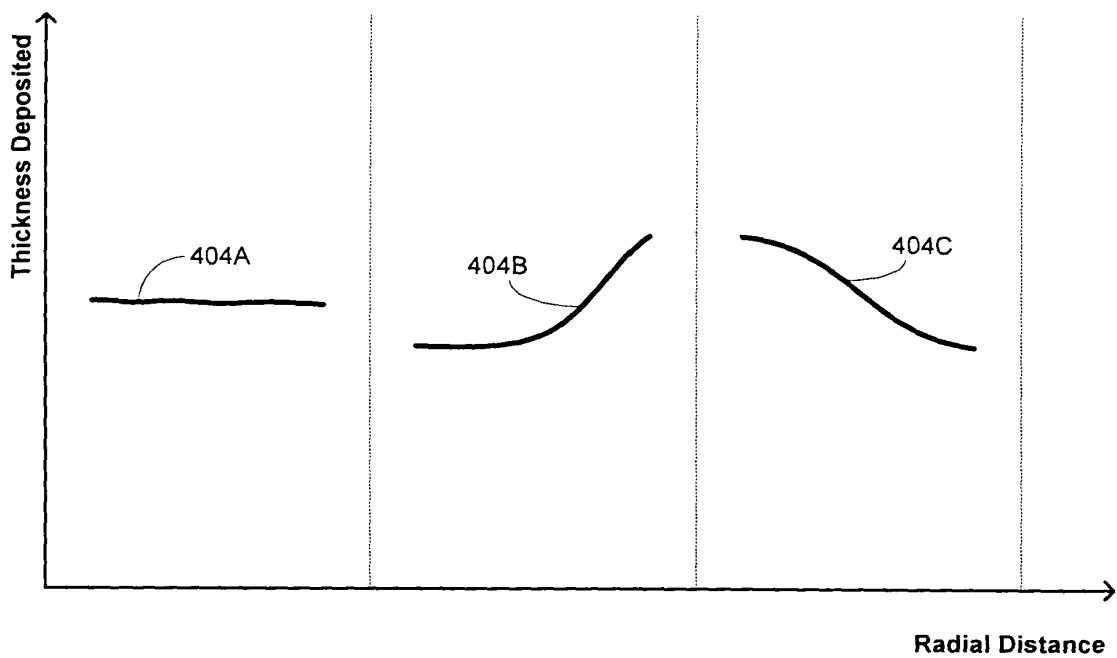
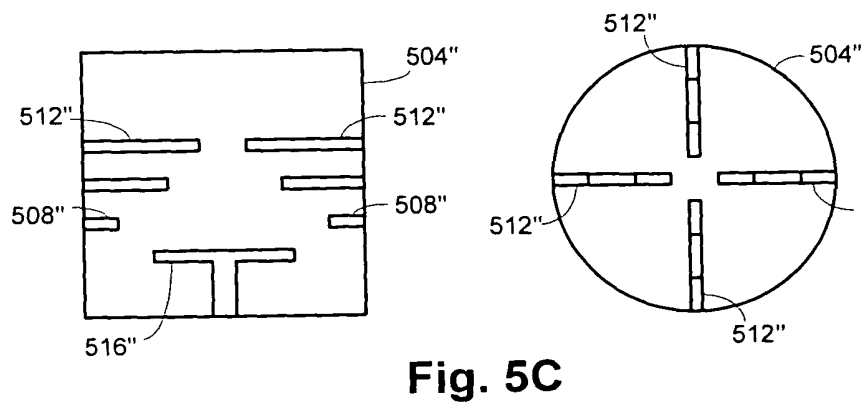
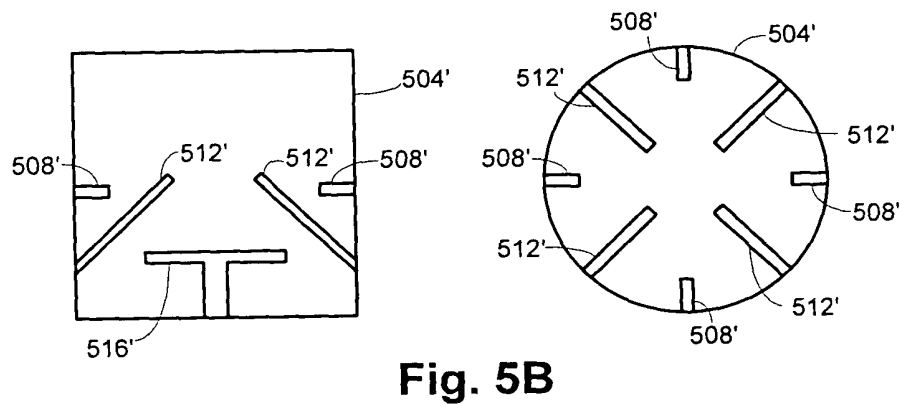
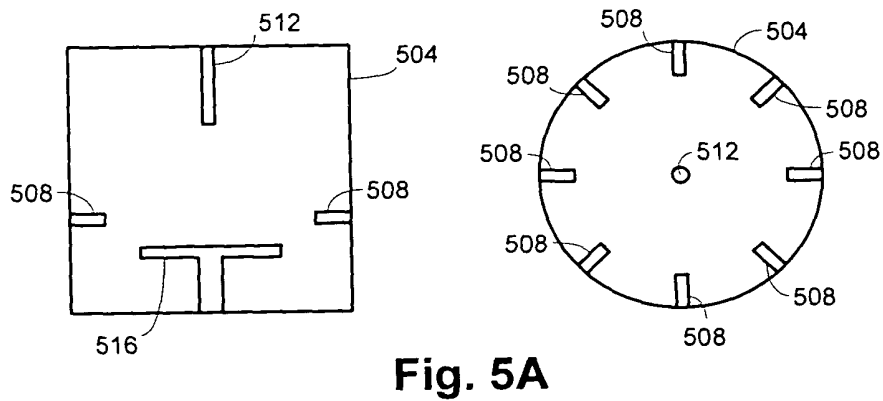
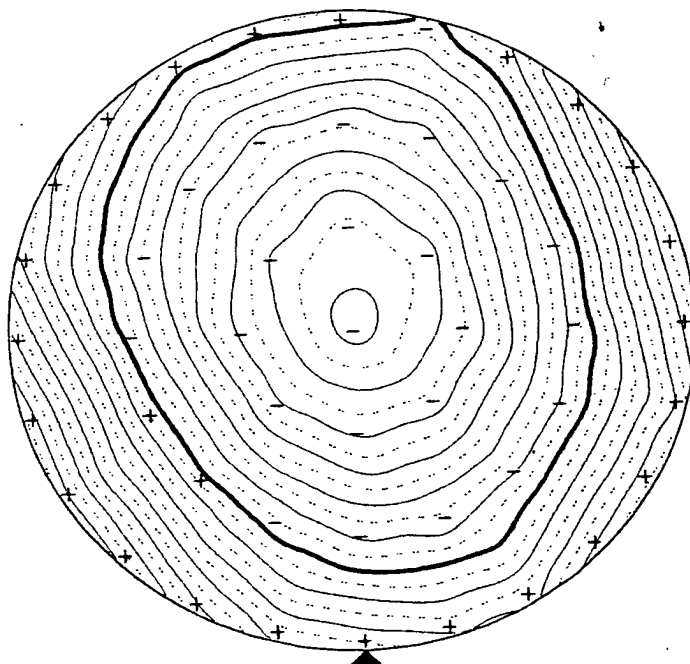


Fig. 4



NANOMETRICS 2D CONTOUR MAP

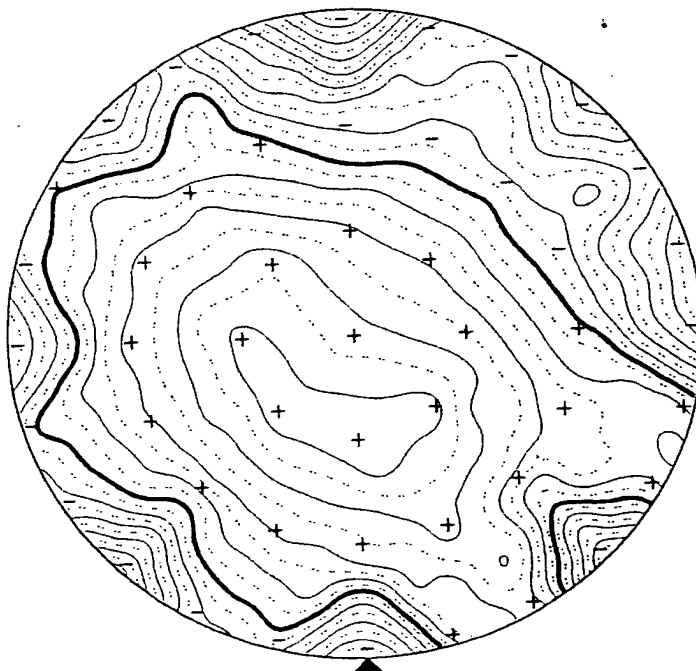


Wafer Size: 200mm
Edge Exclusion: 3.0mm
Points: 49 out of 49

Statistics Data:
Mean: 613Å
StdD: 154.4Å
ZStdD: 25.17%
ZNonU: 47.02%
Max: 898Å
Min: 321Å
Range: 577Å
Interval: 23.1Å
ZInterval: 3.762%
Comment:

Fig. 5D

NANOMETRICS 2D CONTOUR MAP



Wafer Size: 200mm
Edge Exclusion: 3.0mm
Points: 49 out of 49

Statistics Data:
Mean: 488Å
StdD: 46.3Å
ZStdD: 9.48%
ZNonU: 20.67%
Max: 561Å
Min: 359Å
Range: 202Å
Interval: 8.1Å
ZInterval: 1.654%
Comment:
#7

Fig. 5E

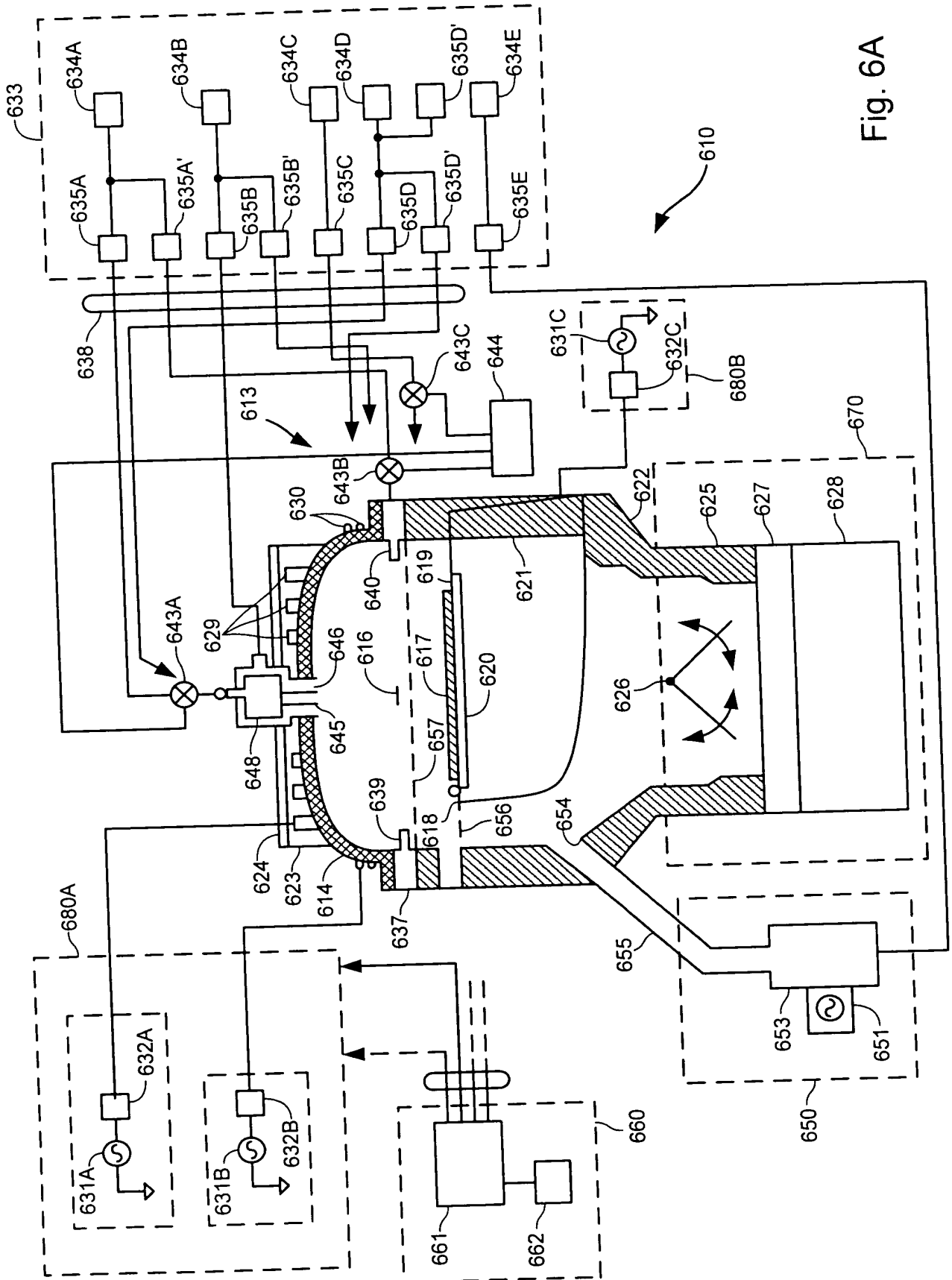
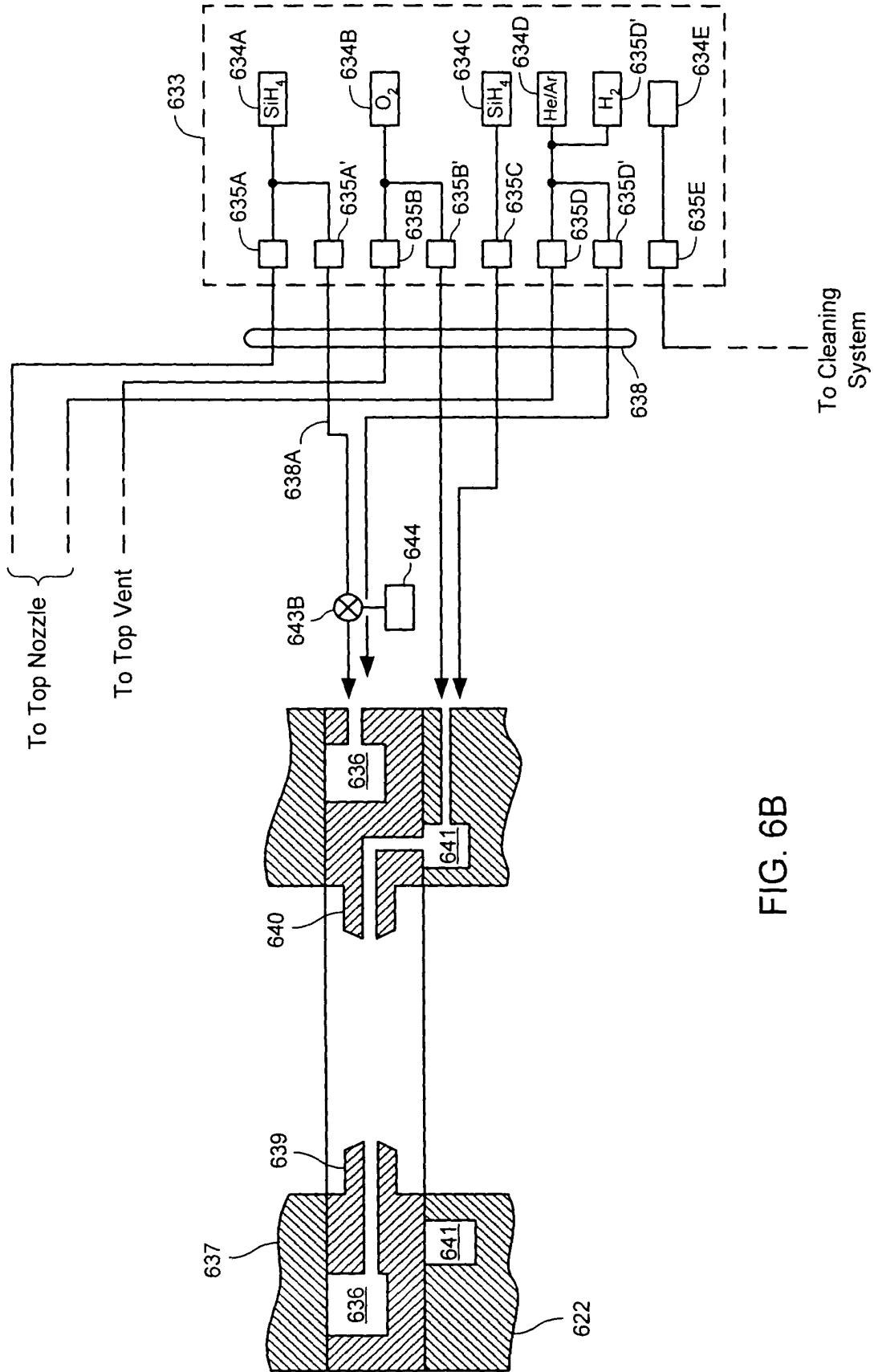


Fig. 6A



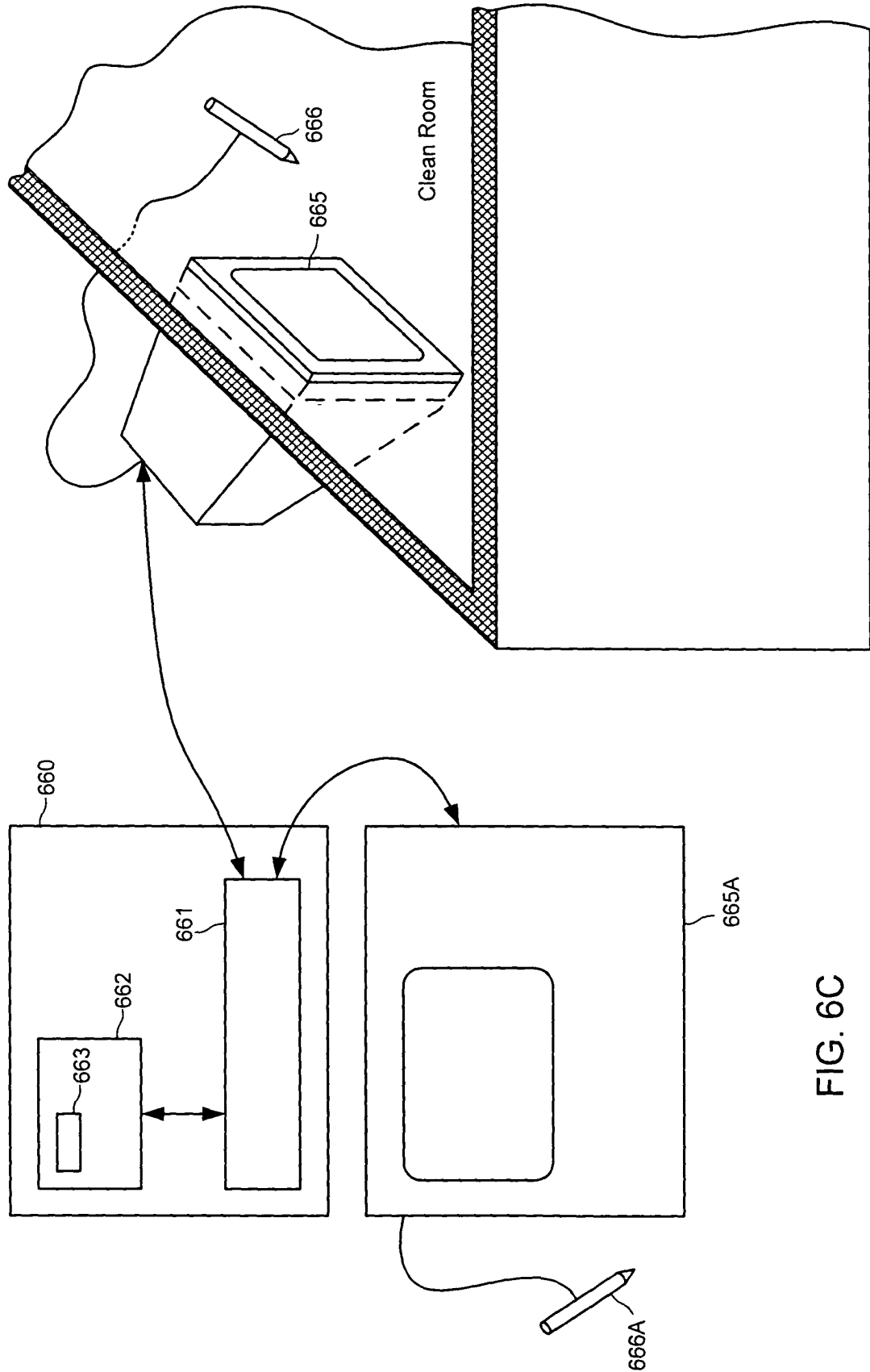


FIG. 6C

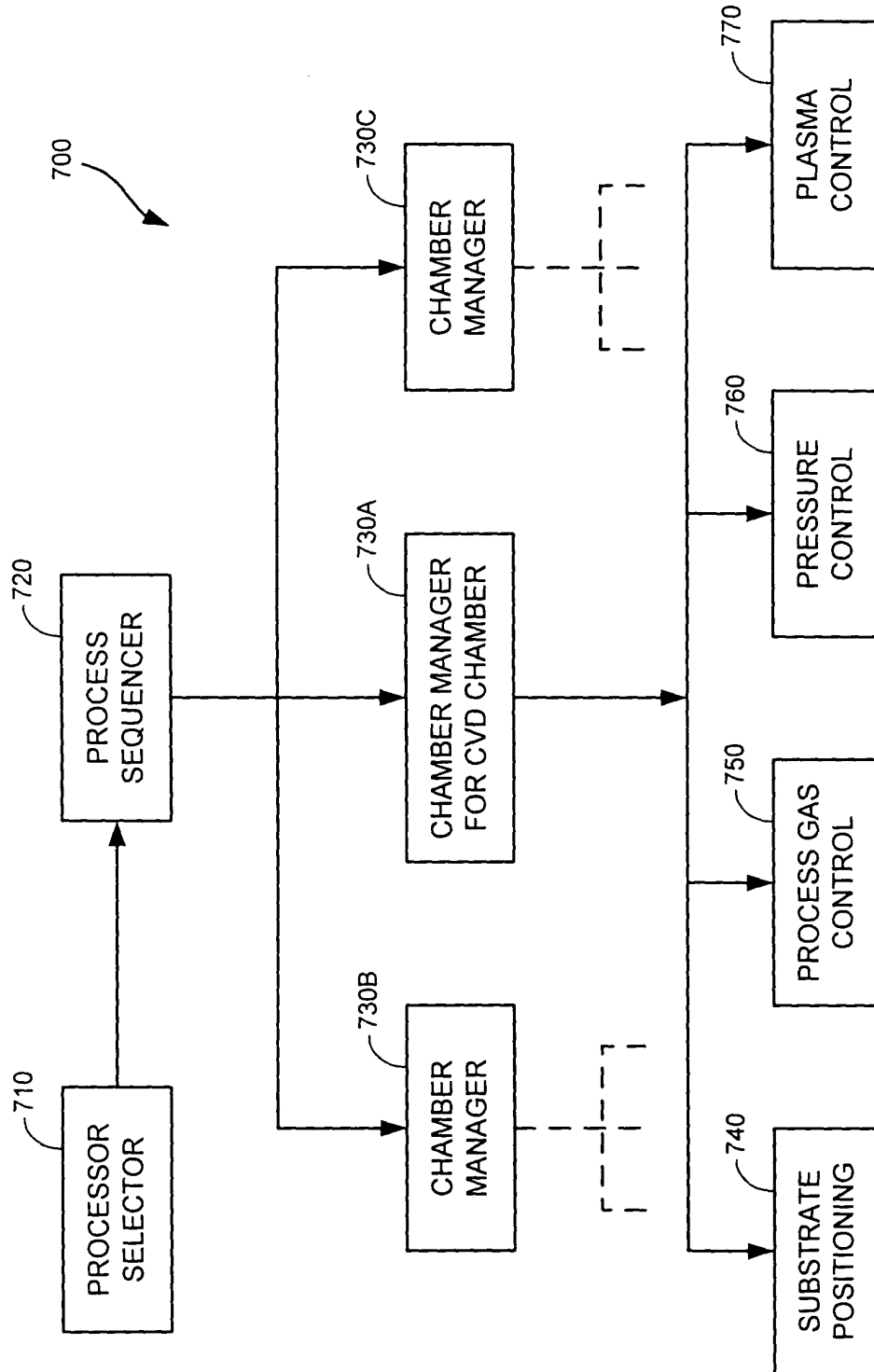


FIG. 6D

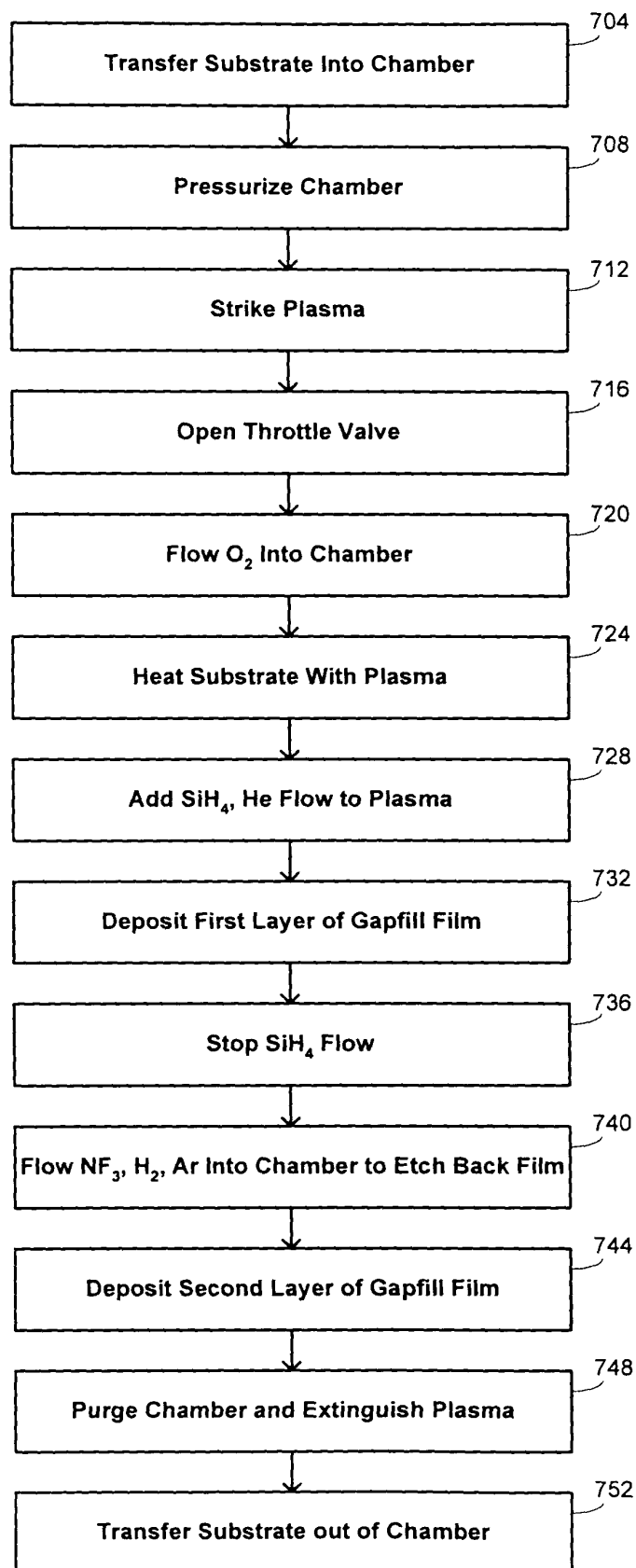


Fig. 7